



Subject card

|   |   |  |  |            |  |         |     |
|---|---|--|--|------------|--|---------|-----|
| Subject name and code                       | Metrology, PG_00047552  |  |  |            |  |         |     |
| Field of study                              | Electronics and Telecommunications  |  |  |            |  |         |     |
| Date of commencement of studies             | October 2024  | Academic year of realisation of subject                  |  |            | 2024/2025  |         |     |
| Education level                             | first-cycle studies   | Subject group  |  |            | Obligatory subject group in the field of study<br>Subject group related to scientific research in the field of study |         |     |
| Mode of study                               | Full-time studies   | Mode of delivery   |  |            | at the university  |         |     |
| Year of study                               | 1   | Language of instruction                                  |  |            | Polish   |         |     |
| Semester of study                           | 2   | ECTS credits   |  |            | 1.0  |         |     |
| Learning profile                            | general academic profile  | Assessment form  |  |            | assessment   |         |     |
| Conducting unit                             | Department of Metrology and Optoelectronics -> Faculty of Electronics, Telecommunications and Informatics   |  |  |            |  |         |     |
| Name and surname of lecturer (lecturers)    | Subject supervisor  |  | dr inż. Sylwia Babicz-Kiewlicz   |            |  |         |     |
|   | Teachers  |  | dr inż. Sylwia Babicz-Kiewlicz   |            |  |         |     |
| Lesson types and methods of instruction     | Lesson type   | Lecture  | Tutorial   | Laboratory | Project  | Seminar | SUM |
|   | Number of study hours   | 15.0   | 0.0  | 0.0        | 0.0  | 0.0     | 15  |
|   | E-learning hours included: 0.0  |  |  |            |  |         |     |
| Learning activity and number of study hours | Learning activity   | Participation in didactic classes included in study plan | Participation in consultation hours  |            | Self-study   | SUM     |     |
|   | Number of study hours   | 15   | 1.0  |            | 9.0  | 25      |     |
| Subject objectives                          | The aim is introduction to : the essence of measurement, units and standards, methods of measurement, analysis of measurement uncertainty, basic instruments for measurement of electrical quantities.  |  |  |            |  |         |     |
| Learning outcomes                           | Course outcome  |  | Subject outcome  |            | Method of verification   |         |     |
|   | [K6_W03] Knows and understands, to an advanced extent, the construction and operating principles of components and systems related to the field of study, including theories, methods and complex relationships between them and selected specific issues - appropriate for the curriculum          |  | Student knows the structure and metrological properties of instruments for measuring basic electrical quantities. He knows the principles of operation of analog / digital converters. Student knows the methods of constructing measurement systems.  |            | [SW1] Assessment of factual knowledge  |         |     |
|   | [K6_W02] knows and understands, to an advanced extent, selected laws of physics and physical phenomena as well as methods and theories explaining the complex relationships between them, constituting the basic general knowledge in the field of technical sciences related to the field of study |  | He knows the basic metrological terms. He knows the measurement methods. It strictly defines the measurand (mierzand). It presents the results of measurements according to the recommendations of the International System of Units (SI), using the correct markings and prefixes to create multiple and submultiple units of measurement. Student analyzes systematic errors in direct and indirect measurements. Student knows the causes of measurement uncertainty and methods of its minimization during measurements. Assesses the measurement uncertainty with the A-method and B-methods. |            | [SW1] Assessment of factual knowledge  |         |     |

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| Subject contents | 1. Introduction, basic metrological terms, classification of measurement methods 2. Measurement errors, types of errors: systematic, random, gross 3. Permanent-magnet moving-coil instrument and its application 4. Digital methods of low and high frequency measurements 5. Digital methods of time-interval and phase measurements 6. Dual-slope integration ADC 7. Immunity of integration ADCs from disturbances 8. Flash and subranging ADC 9. Digital multimeters: architecture, resistance to voltage converter, current to voltage converter, multiterminal inputs 10. AC voltage measurements, waveform parameters, average value, peak value and RMS measurements 11. Oscilloscope: architecture, principles of operation 12. Measurements of voltage, frequency, phase, parameters of pulse, display of device characteristics 13. Measurement uncertainty 14. Measurement methods of impedance parameters R, L, C,  Z  15. Measuring systems and virtual instruments. |
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| <p><b>Prerequisites and co-requisites</b></p> | <p>Presentations from the lectures are only auxiliary materials. Providing students with a presentation does not exempt them from the need to take their own lecture notes and does not replace the independent study of the applicable textbooks. The lecture is only a supplement to the student's independent work. The colloquium is valid for the scope of the material actually laid out during the lecture and contained in the corresponding fragments of the textbooks given in the list of literature for the lecture.</p> <p>Completion of the lecture in the subject takes place in the multiple-choice test after a minimum of two weeks from the last lecture.</p> <p>Place: rooms EA222 / EA442</p> <p>Groups of 16 people will be admitted to the room and they will solve the test on the e-learning platform on laboratory computers.</p> <p>Time to perform the test: 15 minutes</p> <p>Number of questions: 20 (10 from S. Babicz, 10 from St. Gall)</p> <p>After the time has elapsed, an open sample will be saved automatically.</p> <p>Multiple answers will be possible and the questions are tested with zero-one. So if the answers A and C are correct, then in order to get one point for the question, you need to mark exactly the answers A and C. Any other combination will result in not assigning a point for this question.</p> <p>Baseline results will be known as soon as the test is completed.</p> <p>Grades must be issued by the end of the class. Therefore, the retake date will take place before the end of the class, but not sooner than 5 days after the basic test is written.</p> <p>The maximum grade that can be obtained from the resit date is 3.</p> <p>Percentage thresholds for individual ratings:</p> <p>&lt;0; 49&gt;% 2</p> <p>&lt;50; 60&gt;% 3</p> <p>&lt;60; 70&gt;% 3.5</p> <p>&lt;70; 80&gt;% 4</p> <p>&lt;80; 90&gt;% 4.5</p> <p>&lt;90; 100&gt;% 5</p> <p>It is not possible to increase the grade / performance of an additional task for a higher grade etc.</p> |                               |  |                          |                   |                               |            |       |        |
|---|---|-------------------------------|--|--------------------------|-------------------|-------------------------------|------------|-------|--------|
| <p><b>Assessment methods and criteria</b></p> | <table border="1"> <thead> <tr> <th data-bbox="443 1883 794 1921">Subject passing criteria</th> <th data-bbox="794 1883 1139 1921">Passing threshold</th> <th data-bbox="1139 1883 1495 1921">Percentage of the final grade</th> </tr> </thead> <tbody> <tr> <td data-bbox="443 1921 794 1960">Colloquium</td> <td data-bbox="794 1921 1139 1960">50.0%</td> <td data-bbox="1139 1921 1495 1960">100.0%</td> </tr> </tbody> </table>  |                               |  | Subject passing criteria | Passing threshold | Percentage of the final grade | Colloquium | 50.0% | 100.0% |
| Subject passing criteria                      | Passing threshold   | Percentage of the final grade |  |                          |                   |                               |            |       |        |
| Colloquium                                    | 50.0%   | 100.0%                        |  |                          |                   |                               |            |       |        |

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| Recommended reading  | Basic literature  | <ul style="list-style-type: none"> <li>• Piotrowski J., Podstawy Metrologii, PWN 1977</li> <li>• Piotrowski J., Podstawy miernictwa, WNT 2000</li> <li>• Parचाński J., Miernictwo elektryczne i elektroniczne, WSP 1998</li> <li>• Jaworski J., Morawski R., Olędzki J., Wstęp do metrologii i techniki eksperymentu, WNT 1992</li> <li>• Piotrowski J., Podstawy metrologii, Politechnika Śląska 1971</li> <li>• Taylor J. R., Wstęp do analizy błędów pomiarowych, PWN 1999</li> <li>• Tumański S., Technika pomiarowa, WNT 2007</li> <li>• Chwaleba A., Poniński M., Siedlecki A., Metrologia elektryczna, WNT 2009</li> </ul> |
|  | Supplementary literature  | <ul style="list-style-type: none"> <li>• Domańska A., Barzykowski J., Kujawińska M., <i>Współczesna metrologia wybrane zagadnienia</i>, WNT 2016</li> <li>• Jakubiec W., Malinowski J., <i>Metrologia wielkości geometrycznych</i>, PWN 2018</li> <li>• Bewoor A. K., Kulkarni V. A., <i>Metrology &amp; Measurements</i>, Tata McGraw-Hill Education 2009 (dostępna częściowo w books.gogle)</li> <li>• Banerjee G. K., <i>Electrical And Electronic Measurements</i>, PHI Learning Pvt. Ltd (books.gogle)</li> </ul>  |
|  | eResources addresses  | Adresy na platformie eNauczanie:  |
| Example issues/<br>example questions/<br>tasks being completed | <p>1 Two voltmeters could be used to measure the voltage <math>U = 12\text{ V}</math>. The first was a class 0.5 laboratory voltmeter with a measuring range of 60 V, and the second was a class 1.5 blackboard voltmeter with a measuring range of 15 V. Which voltmeter allowed the voltage value to be determined with less error?2) What is the measured frequency if 3587 pulses were counted in the 10 ms gate-opening time of the frequency meter.3. a frequency meter, normally operating with an internal reference frequency source of 1 MHz, was used with an external reference generator of 4 MHz. How should the frequency measurement results be corrected: (a) multiply by 4, (b) multiply by 2, (c) divide by 4.4. represent in the figure the voltage waveform that occurs at the output of the integrator in an A/D converter with double integration processing. Mark with "a" the time interval in which the reference voltage is integrated, with "b" the time interval in which the measured voltage is integrated, with "c" the time interval proportional to the measured voltage, with "d" the moment when the state of the comparator output changes, with "e" the moment when the counter overflows, with "f" the time interval which is to be equal to 20 ms to ensure immunity of the converter to mains frequency interference.The Y channel of the oscilloscope has a bandwidth of 40 MHz. What is the rise time of the step response of the oscilloscope. What is the rise time of the pulse you will read from the screen of this oscilloscope if you are testing a pulse whose rise time is 20 ns.6. The uncertainty of the voltage measurement is expressed in the multimeter specification as <math>\pm(1\%+2\text{ digits})</math> and the reading is 1.200 V. Calculate the uncertainty of the voltage measurement.7 Explain the meaning of the abbreviations read from the face plate of the multimeter: AC, DC, 2W, 4W.8. Express the voltage ratios in dB: <math>U_1/U_2 = 103</math>, 1, 10-2.9. give the rms and peak-to-peak value of the voltage in a domestic power network.10. Why is a four-wire connection between a resistor and a measuring instrument used when measuring small resistances?</p> |   |
| Work placement   | Not applicable  |   |